4th International Conference "2021 Devices for Integrated Circuit (DevIC)"

Organized by IEEE KGEC Student Branch Chapter in association with Dept. of ECE, KGEC

IEEE Conference Record No. #50843

19-20 May, 2021

Online Mode Conference

Venue: Kalyani Government Engineering College

TOPICS OF INTEREST: Papers are solicited across the general field of electronic devices and their applications in circuits, systems and high frequency wireless communication

Homepage:

https://edu.ieee.org/in-kgec/devic-conference/devic-2021-home-page/

Publication

All the accepted papers will be submitted for inclusion into IEEE Xplore after being presented in the conference.

Journal Publication of Extended version of selected papers (No extra Fee)

Special Issue in Computers & Electrical Engineering (SCI Indexed), Published by Elsevier

Special Issue in Journal of Materials Science: Materials in Electronics (SCI Indexed), Published by Springer

Special issue in Physica Scripta (SCI Indexed), Published by IOP Science, UK

Special Issue in Journal of Micromechanics and Microengineering (SCI Indexed), published by IOP, UK

Special issue in Micro and Nanosystems (Scopus Indexed) published by Bentham Science Publishers

Special Issue in International Journal of Nanoparticles (Scopus Indexed), published by InderScience

Special Issue in International Journal of High Speed Electronics and Systems (Scopus Indexed), published by World Scientific Pte. Ltd.

Special Issue in Facta Universitatis, Series: Electronics and Energetics (ESCI), published by FU, Serbia

Special Issue in Solid State Electronics Letters, published by KeAi Communicartions with publishing services by Elsevier

Topical Collection in Springer Nature's (SN) journal SN Applied Sciences, Published by Springer

Selected papers will be uploaded to Micro System Technologies (SCIE Indexed), published by Springer

Selected papers will be uploaded to Int. Journal of Numerical Modelling: International Journal of Numerical Modelling: Electronic Networks, Devices and Fields (IJNM) (SCIE Indexed), published by Willey